

# UNISONIC TECHNOLOGIES CO., LTD

1N150-E4 Preliminary Power MOSFET

# 1.0A, 1500V N-CHANNEL POWER MOSFET

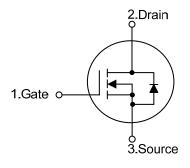
#### **■** DESCRIPTION

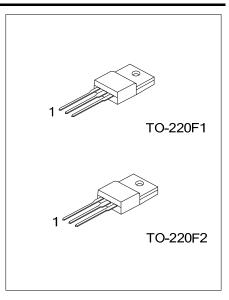
The UTC **1N150-E4** provide excellent  $R_{DS(ON)}$ , low gate charge and operation with low gate voltages. This device is suitable for use as a load switch or in PWM applications.

#### ■ FEATURESO

- \*  $R_{DS(ON)} \le 16 \Omega$  @  $V_{GS}=10V$ ,  $I_D=0.5A$
- \* Low Reverse Transfer Capacitance
- \* Fast Switching Capability
- \* Avalanche Energy Specified
- \* Improved dv/dt Capability, High Ruggedness

#### ■ SYMBOL

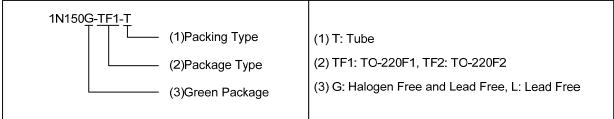




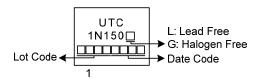
# ORDERING INFORMATION

Ordering Number		Daalsaaa	Pin Assignment			Daakina	
Lead Free	Halogen Free	Package	1	2	3	Packing	
1N150L-TF1-T	1N150G-TF1-T	TO-220F1	G	D	S	Tube	
1N150L-TF2-T	1N150G-TF2-T	TO-220F2	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



#### ■ MARKING



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# ■ **ABSOLUTE MAXIMUM RATINGS** (T<sub>C</sub>=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		$V_{ extsf{DSS}}$	1500	V	
Gate-Source Voltage		$V_{GSS}$	±30	V	
Drain Current	Continuous	I <sub>D</sub>	1	Α	
	Pulsed (Note 2)	I <sub>DM</sub>	2	Α	
Avalanche Energy	Single Pulsed (Note 3)	E <sub>AS</sub>	43	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3.2	V/ns	
Power Dissipation		$P_{D}$	15	W	
Junction Temperature		$T_J$	+150	°C	
Storage Temperature		T <sub>STG</sub>	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=30mH,  $I_{AS}$ =1.7A,  $V_{DD}$ =150V,  $R_{G}$ =25  $\Omega$ , Starting  $T_{J}$  = 25°C
- 4.  $I_{SD} \le 1.0 A$ , di/dt  $\le 200 A/\mu s$ ,  $V_{DD} \le BV_{DSS}$ , Starting  $T_J = 25 ^{\circ}C$

# ■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	$\theta_{JA}$	62.5	°C/W	
Junction to Case	$\theta_{JC}$	8.3	°C/W	

# ■ ELECTRICAL CHARACTERISTICS (T<sub>J</sub> =25°C, unless otherwise specified)

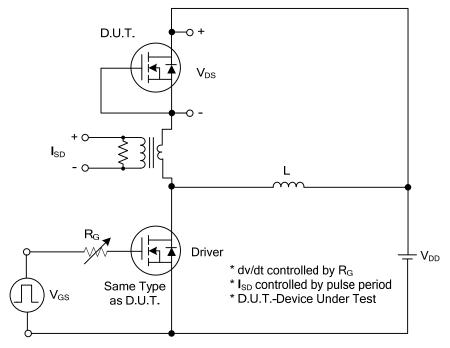
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage	$BV_{DSS}$	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA				V		
Drain-Source Leakage Current	$I_{DSS}$	V <sub>DS</sub> =1500V, V <sub>GS</sub> =0V			10	μΑ		
Gate-Source Leakage Current	rent I <sub>GSS</sub> V <sub>GS</sub> =±30V, V <sub>DS</sub> =0V				±100	nA		
ON CHARACTERISTICS								
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	3.0		5.0	V		
Static Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =0.5A			16	Ω		
DYNAMIC CHARACTERISTICS								
Input Capacitance	C <sub>ISS</sub>			390		рF		
Output Capacitance	Coss	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1MHz		43		рF		
Reverse Transfer Capacitance	$C_{RSS}$			14		рF		
SWITCHING CHARACTERISTICS								
Total Gate Charge (Note 1)	$Q_G$	V <sub>DS</sub> =1200V, V <sub>GS</sub> =10V, I <sub>D</sub> =1.0A (Note 1, 2)		24		nC		
Gate-Source Charge	$Q_GS$			9		nC		
Gate-Drain Charge	$Q_GD$			8		nC		
Turn-On Delay Time (Note 1)	$t_{D(ON)}$			7.6		ns		
Turn-On Rise Time	$t_R$	V <sub>DD</sub> =100V, V <sub>GS</sub> =10V,		17		ns		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	$I_D=1.0A$ , $R_G=25\Omega$ (Note 1, 2)		36		ns		
Turn-Off Fall Time	$t_{F}$	]		74		ns		
SOURCE- DRAIN DIODE RATINGS AND CHA	ARACTERISTI	cs						
Maximum Continuous Drain-Source Diode					1	^		
Forward Current	I <sub>S</sub>				ı	Α		
Maximum Pulsed Drain-Source Diode	1				2	Α		
Forward Current	I <sub>SM</sub>					A		
Drain-Source Diode Forward Voltage (Note 1)	$V_{SD}$	I <sub>S</sub> =1.0A, V <sub>GS</sub> =0V			1.4	V		
Body Diode Reverse Recovery Time (Note 1)	t <sub>rr</sub>	I <sub>S</sub> =1.0A, V <sub>GS</sub> =0V,		765		nS		
Body Diode Reverse Recovery Charge	$Q_{rr}$	dI <sub>F</sub> /dt=100A/μs		3.3		μC		

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle≤2%.

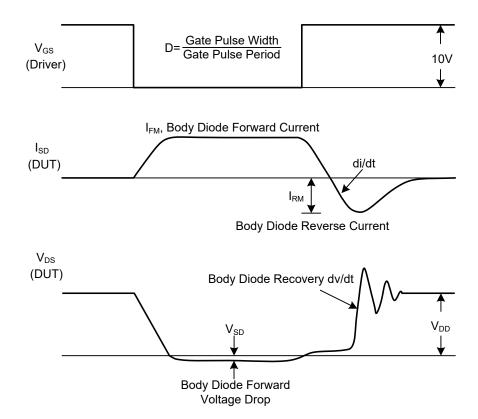
2. Essentially independent of operating temperature.



# ■ TEST CIRCUITS AND WAVEFORMS

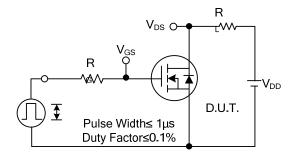


Peak Diode Recovery dv/dt Test Circuit

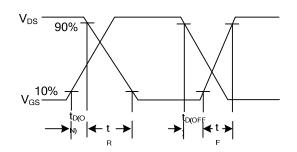


Peak Diode Recovery dv/dt Waveforms

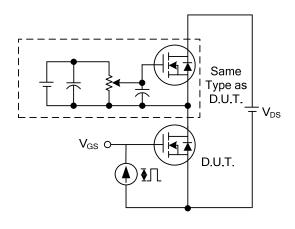
# ■ TEST CIRCUITS AND WAVEFORMS



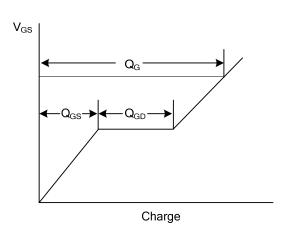
**Switching Test Circuit** 



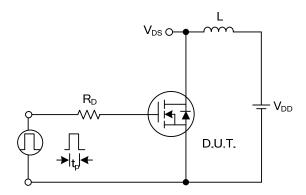
Switching Waveforms



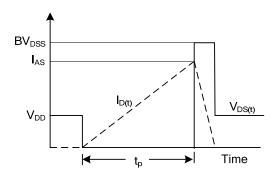
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



**Unclamped Inductive Switching Waveforms** 

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